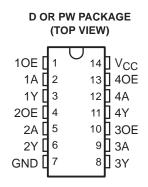
SN74AHCT126-EP QUADRUPLE BUS BUFFER GATES WITH 3-STATE OUTPUTS SCLS551 – DECEMBER 2003

- Controlled Baseline

 One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of -40°C to 125°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree[†]
- [†] Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Inputs Are TTL-Voltage Compatible



description

The SN74AHCT126 device is a quadruple bus buffer gate featuring independent line drivers with 3-state outputs. Each output is disabled when the associated output-enable (OE) input is low. When OE is high, the respective gate passes the data from the A input to its Y output.

To ensure the high-impedance state during power up or power down, OE should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

ORDERING INFORMATION

| TA | PACKA | GE‡ | ORDERABLE PART NUMBER | TOP-SIDE MARKING |
|----------------|------------|---------------|--------------------------|---------------------|
| -40°C to 125°C | SOIC – D | Tape and reel | SN74AHCT126QDREP | AHCT126QEP |
| -40 C 10 125°C | TSSOP – PW | Tape and reel | SN74AHCT126QPWREP | HB126EP |

[‡] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

| FUNCTION TABLE (each buffer) | | | | | | | | | | |
|---------------------------------|---|---|--|--|--|--|--|--|--|--|
| INPUTS OUTPUT | | | | | | | | | | |
| OE | Α | Y | | | | | | | | |
| Н | Н | Н | | | | | | | | |
| н | L | L | | | | | | | | |
| L | Х | Z | | | | | | | | |



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

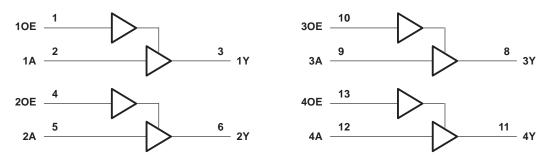
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN74AHCT126-EP QUADRUPLE BUS BUFFER GATES WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

| Supply voltage range, V _{CC} | –0.5 V to 7 V |
|--|----------------|
| Input voltage range, V _I (see Note 1) | |
| Output voltage range, V_{O} (see Note 1) | |
| | |
| Input clamp current, I _{IK} (V _I < 0) | –20 mA |
| Output clamp current, I_{OK} (V _O < 0 or V _O > V _{CC}) | ±20 mA |
| Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$ | ±25 mA |
| Continuous current through V _{CC} or GND | ±50 mA |
| Package thermal impedance, θ_{JA} (see Note 2): D package | |
| PW package | 113°C/W |
| Storage temperature range, T _{stg} | –65°C to 150°C |

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 3)

| | | MIN | MAX | UNIT |
|---------------------|------------------------------------|-----|-----|------|
| VCC | Supply voltage | 4.5 | 5.5 | V |
| VIH | High-level input voltage | 2 | | V |
| VIL | Low-level input voltage | | 0.8 | V |
| VI | Input voltage | 0 | 5.5 | V |
| VO | Output voltage | 0 | VCC | V |
| IOH | High-level output current | | -8 | mA |
| IOL | Low-level output current | | 8 | mA |
| $\Delta t/\Delta v$ | Input transition rise or fall rate | | 20 | ns/V |
| ТĄ | Operating free-air temperature | -40 | 125 | °C |

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



SN74AHCT126-EP **QUADRUPLE BUS BUFFER GATES** WITH 3-STATE OUTPUTS SCLS551 - DECEMBER 2003

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| DADAMETER | TEAT CONDITIONS | | T, | 4 = 25° Ω | ; | | | |
|-----------|---|--------------|------|------------------|-------|-----|------|------|
| PARAMETER | TEST CONDITIONS | VCC | MIN | TYP | MAX | MIN | MAX | UNIT |
| Maria | I _{OH} = -50 μA | 4.5 V | 4.4 | 4.5 | | 4.4 | | V |
| VOH | I _{OH} = -8 mA | 4.5 V | 3.94 | | | 3.8 | | V |
| Max | I _{OL} = 50 μA | 4.5.1/ | | | 0.1 | | 0.1 | |
| VOL | I _{OL} = 8 mA | 4.5 V | | | 0.36 | | 0.44 | V |
| lı | $V_I = 5.5 V \text{ or GND}$ | 0 V to 5.5 V | | | ±0.1 | | ±1 | μA |
| loz | $V_{O} = V_{CC}$ or GND | 5.5 V | | | ±0.25 | | ±2.5 | μA |
| Icc | $V_{I} = V_{CC} \text{ or } GND,$ $I_{O} = 0$ | 5.5 V | | | 2 | | 20 | μΑ |
| ∆ICC‡ | One input at 3.4 V, Other inputs at V_{CC} or GND | 5.5 V | | | 1.35 | | 1.5 | mA |
| Ci | $V_I = V_{CC}$ or GND | 5 V | | 4 | 10 | | | pF |
| Co | $V_{O} = V_{CC}$ or GND | 5 V | | 15 | | | | pF |

[†] This is the increase in supply current for each input at one of the specified TTL voltage levels, rather than 0 V or V_{CC}.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

| DADAMETED | FROM | то | LOAD | Τ ₄ | ∖ = 25°C | ; | MIN | | |
|--------------------|---------|----------|------------------------|----------------|-----------------|-----|-----|-----|------|
| PARAMETER | (INPUT) | (OUTPUT) | CAPACITANCE | MIN | TYP | MAX | MIN | MAX | UNIT |
| ^t PLH | А | Y | 0. 15 55 | | 3.8 | 5.5 | 1 | 6.5 | 20 |
| ^t PHL | A | ř | C _L = 15 pF | | 3.8 | 5.5 | 1 | 6.5 | ns |
| ^t PZH | OE | V | 0. 15 55 | | 3.6 | 5.1 | 1 | 6 | 2 |
| ^t PZL | UE | Y | C _L = 15 pF | | 3.6 | 5.1 | 1 | 6 | ns |
| ^t PHZ | OE | Y | CL = 15 pF | | 4.6 | 6.8 | 1 | 8 | ns |
| ^t PLZ | UE | I | CL = 13 pr | | 4.6 | 6.8 | 1 | 8 | 113 |
| ^t PLH | | X | 0 50 5 | | 5.3 | 7.5 | 1 | 8.5 | |
| ^t PHL | А | Y | C _L = 50 pF | | 5.3 | 7.5 | 1 | 8.5 | ns |
| ^t PZH | 05 | X | 0 50 5 | | 5.1 | 7.1 | 1 | 8 | |
| ^t PZL | OE | Y | C _L = 50 pF | | 5.1 | 7.1 | 1 | 8 | ns |
| ^t PHZ | 05 | V | 0 50 0 5 | | 6.1 | 8.8 | 1 | 10 | |
| ^t PLZ | OE | Y | C _L = 50 pF | | 6.1 | 8.8 | 1 | 10 | ns |
| ^t sk(o) | | | C _L = 50 pF | | | 1 | | | ns |

noise characteristics, V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C (see Note 4)

| | PARAMETER | MIN | MAX | UNIT |
|--------------------|---|-----|------|------|
| VOL(P) | Quiet output, maximum dynamic V _{OL} | | 0.8 | V |
| VOL(V) | Quiet output, minimum dynamic V _{OL} | | -0.8 | V |
| VOH(V) | Quiet output, minimum dynamic V _{OH} | 4.4 | | V |
| VIH(D) | High-level dynamic input voltage | 2 | | V |
| V _{IL(D)} | Low-level dynamic input voltage | | 0.8 | V |

NOTE 4: Characteristics are for surface-mount packages only.

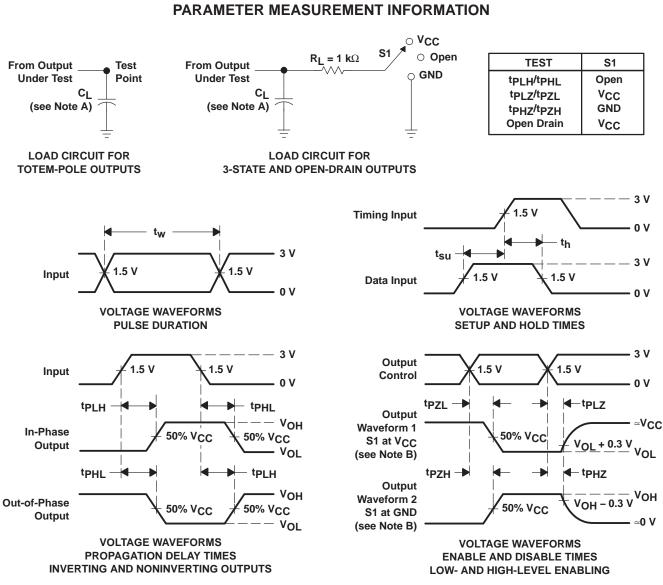


SN74AHCT126-EP QUADRUPLE BUS BUFFER GATES WITH 3-STATE OUTPUTS

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operating characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$

| | PARAMETER | TEST C | ONDITIONS | TYP | UNIT |
|-----|-------------------------------|----------|-----------|-----|------|
| Cpd | Power dissipation capacitance | No load, | f = 1 MHz | 14 | pF |



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f \leq 3 ns, t_f \leq 3 ns.

D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms





PACKAGING INFORMATION

| Orderable Device | | Package Type | Package Drawing | Pins | Package Qty | | Lead finish/ Ball material | MSL Peak Temp | Op Temp (°C) | Device Marking | Samples |
|-------------------|--------|--------------|--------------------|------|----------------|--------------|-------------------------------|--------------------|--------------|----------------|---------|
| | (1) | | Drawing | | aly | (2) | (6) | (3) | | (4/5) | |
| SN74AHCT126QDREP | ACTIVE | SOIC | D | 14 | 2500 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 125 | AHCT126QEP | Samples |
| SN74AHCT126QPWREP | ACTIVE | TSSOP | PW | 14 | 2000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 125 | HB126EP | Samples |
| V62/04684-01XE | ACTIVE | SOIC | D | 14 | 2500 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 125 | AHCT126QEP | Samples |
| V62/04684-01YE | ACTIVE | TSSOP | PW | 14 | 2000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 125 | HB126EP | Samples |

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

10-Dec-2020

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OTHER QUALIFIED VERSIONS OF SN74AHCT126-EP:

- Catalog: SN74AHCT126
- Automotive: SN74AHCT126-Q1
- Military: SN54AHCT126

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



| *All dimensions are nominal | | | | | | | | | | | | |
|-----------------------------|-----------------|--------------------|----|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| Device | Package Type | Package Drawing | | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
| SN74AHCT126QDREP | SOIC | D | 14 | 2500 | 330.0 | 16.4 | 6.5 | 9.0 | 2.1 | 8.0 | 16.0 | Q1 |
| SN74AHCT126QPWREP | TSSOP | PW | 14 | 2000 | 330.0 | 12.4 | 6.9 | 5.6 | 1.6 | 8.0 | 12.0 | Q1 |

TEXAS INSTRUMENTS

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PACKAGE MATERIALS INFORMATION

16-Oct-2020



*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|-------------------|--------------|-----------------|------|------|-------------|------------|-------------|
| SN74AHCT126QDREP | SOIC | D | 14 | 2500 | 333.2 | 345.9 | 28.6 |
| SN74AHCT126QPWREP | TSSOP | PW | 14 | 2000 | 853.0 | 449.0 | 35.0 |

D (R-PDSO-G14)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AB.





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
 E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G14)

PLASTIC SMALL OUTLINE



A. An integration of the information o

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.

Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.

E. Falls within JEDEC MO-153





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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